Γ

<u>询"TLV5535-Q1"供应商</u>

- Meets AEC-Q100-011 C3A CDM Classification
- Qualified for Automotive Applications
- 8-Bit Resolution, 35 MSPS Sampling Analog-to-Digital Converter (ADC)
- Low Power Consumption: 90 mW Typ
 Using External References
- Wide Analog Input Bandwidth: 600 MHz Typ
- 3.3-V Single-Supply Operation
- 3.3-V TTL/CMOS-Compatible Digital I/O
- Internal Bottom and Top Reference Voltages
- Adjustable Reference Input Range
- Power-Down (Standby) Mode
- Separate Power Down for Internal Voltage References
- Three-State Outputs
- 28-Pin Thin Shrink SOP (TSSOP) Packages
- Applications
 - Digital Communications (IF Sampling)
 - High-Speed DSP Front-End (TMS320C6000)
 - Video Processing (Scan Rate/Format Conversion)
 - DVD Read Channel Digitization

description/ordering information

The TLV5535 is an 8-bit, 35 MSPS, high-speed A/D converter. It converts the analog input signal into 8-bit binary-coded digital words up to a sampling rate of 35 MHz. All digital inputs and outputs are 3.3 V TTL/CMOS-compatible.

The device consumes very little power due to the 3.3-V supply and an innovative single-pipeline architecture implemented in a CMOS process. The user obtains maximum flexibility by setting both bottom and top voltage references from user-supplied voltages. If no external references are available, on-chip references are available for internal and external use. The full-scale range is 1 V_{pp} up to 1.6 V_{pp} , depending on the analog supply voltage. If external references are available, the internal references can be disabled independently from the rest of the chip, resulting in an even greater power saving.

ORDERING INFORMATION[†]

TJ	PACKAGE [‡]		ORDERABLE PART NUMBER	TOP-SIDE MARKING
–40°C to 85°C	TSSOP (PW)	Tape and reel	TLV5535IPWRQ1	TLV5535Q1

[†] For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at http://www.ti.com.

[‡]Package drawings, thermal data, and symbolization are available at http://www.ti.com/packaging.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



Copyright © 2008 Texas Instruments Incorporated

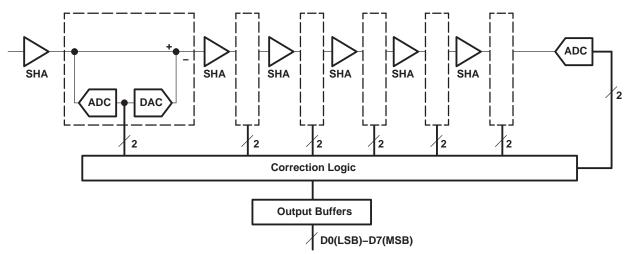
SGLS230A - JANUARY 2004 - REVISED JUNE 2008

Р	W PACI		—
DRV _{DD}	1	28] AV _{SS}
D0 [2	27	AV _{DD}
D1 [3	26	AIN
D2 [4	25	
D3 [5	24	PWDN_REF
D4 [6	23	AV _{SS}
D5 [7	22	REFBO
D6 [8	21	REFBI
D7 [9	20	REFTI
DRV _{SS} [10	19	REFTO
DV _{SS}	11	18	AV _{SS}
CLK [12	17	BG
OE [13	16	AV _{DD}
dv _{dd} [14	15] STBY

description (continued)

While usable in a wide variety of applications, the device is specifically suited for the digitizing of high-speed graphics and for interfacing to LCD panels or LCD/DMD projection modules. Other applications include DVD read channel digitization, medical imaging, and communications. This device is suitable for IF sampling of communication systems using sub-Nyquist sampling methods because of its high analog input bandwidth.

functional block diagram



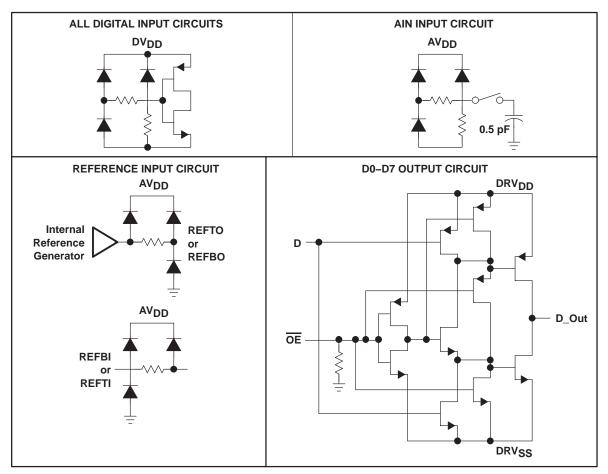
The single-pipeline architecture uses 6 ADC/DAC stages and one final flash ADC. Each stage produces a resolution of 2 bits. The correction logic generates its result using the 2-bit result from the first stage, 1 bit from each of the 5 succeeding stages, and 1 bit from the final stage in order to arrive at an 8-bit result. The correction logic ensures no missing codes over the full operating temperature range.



<u> 查询"TLV5535-Q1"供应商</u>

SGLS230A - JANUARY 2004 - REVISED JUNE 2008

circuit diagrams of inputs and outputs





SGLS2967HUMB52004 OPEVERTIME 2008

TERM	INAL		
NAME	NO.	I/O	DESCRIPTION
AIN	26	Ι	Analog input
AVDD	16, 27	Ι	Analog supply voltage
AVSS	18, 23, 28	Ι	Analog ground
BG	17	0	Band gap reference voltage. A 1- μ F capacitor (with an optional 0.1- μ F capacitor in parallel) should be connected between this terminal and AV _{SS} for external filtering.
CLK	12	Ι	Clock input. The input is sampled on each rising edge of CLK.
CML	25	0	Common mode level. This voltage is equal to $(AV_{DD} - AV_{SS}) \div 2$. An external 0.1- μ F capacitor should be connected between this terminal and AV_{SS} .
D0 – D7	2 – 9	0	Data outputs. D7 is the MSB.
DRV _{DD}	1	Ι	Supply voltage for digital output drivers
DRVSS	10	Ι	Ground for digital output drivers
DVDD	14	Ι	Digital supply voltage
OE	13	Ι	Output enable. When high, the D0 – D7 outputs go in high-impedance mode.
DVSS	11	Ι	Digital ground
PWDN_REF	24	Ι	Power down for internal reference voltages. A high on this terminal disables the internal reference circuit.
REFBI	21	I	Reference voltage bottom input. The voltage at this terminal defines the bottom reference voltage for the ADC. It can be connected to REFBO or to an externally generated reference level. Sufficient filtering should be applied to this input. The use of a 0.1 - μ F capacitor connected between REFBI and AV _{SS} is recommended. Additionally, a 0.1 - μ F capacitor can be connected between REFBI.
REFBO	22	0	Reference voltage bottom output. An internally generated reference is available at this terminal. It can be connected to REFBI or left unconnected. A 1- μ F capacitor between REFBO and AV _{SS} provides sufficient decoupling required for this output.
REFTI	20	I	Reference voltage top input. The voltage at this terminal defines the top reference voltage for the ADC. It can be connected to REFTO or to an externally generated reference level. Sufficient filtering should be applied to this input. The use of a 0.1- μ F capacitor between REFTI and AV _{SS} is recommended. Additionaly, a 0.1- μ F capacitor can be connected between REFTI and REFBI.
REFTO	19	0	Reference voltage top output. An internally generated reference is available at this terminal. It can be connected to REFTI or left unconnected. A 1- μ F capacitor between REFTO and AV _{SS} provides sufficient decoupling required for this output.
STBY	15	1	Standby input. A high level on this input enables power-down mode.

Terminal Functions

absolute maximum ratings over operating free-air temperature (unless otherwise noted)[†]

Supply voltage range: AV _{DD} to AV _{SS} , DV _{DD} to DV _{SS}
Digital input voltage range to DV_{SS}
Analog input voltage range to AV _{SS} –0.5 V to AV _{DD} + 0.5 V
Digital output voltage range applied from external source to DGND
Reference voltage input range to AGND: V(REFTI), V(REFTO), V(REFBI), V(REFBO) -0.5 V to AVDD + 0.5 V
Operating free-air temperature range, T _A : TLV55351
Storage temperature range, T _{stg} –55°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



<u> 查询"TLV5535-Q1"供应商</u>

SGLS230A - JANUARY 2004 - REVISED JUNE 2008

recommended operating conditions over operating free-temperature range

power supply

		MIN	NOM	MAX	UNIT
	AV _{DD} - AV _{SS}				
Supply voltage	DV _{DD} – DV _{SS}	3	3.3	3.6	V
	$DRV_{DD} - DRV_{SS}$				

analog and reference inputs

	MIN	NOM	MAX	UNIT
Reference input voltage (top), V(REFTI)	(NOM) – 0.2	2 + (AV _{DD} – 3)	(NOM) + 0.2	V
Reference input voltage (bottom), V(REFBI)	0.8	1	1.2	V
Reference voltage differential, V(REFTI) - V(REFBI)			$1 + (AV_{DD} - 3)$	V
Analog input voltage, V _(AIN)	V _(REFBI)		V(REFTI)	V

digital inputs

	MIN	NOM MAX	UNIT
High-level input voltage, VIH	2.0	DV _{DD}	V
Low-level input voltage, VIL	DGND	0.2xDV _{DD}	V
Clock period, t _C	28.6		ns
Pulse duration, clock high, tw(CLKH)	13		ns
Pulse duration, clock low, tw(CLKL)	13		ns

electrical characteristics over recommended operating conditions, f_{CLK} = 35 MSPS, external voltage references (unless otherwise noted)

power supply

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
		AV _{DD}			27	34	
IDD		AV _{DD} = DV _{DD} = 3.3 V, DRV _{DD} = 3 V, C _I = 15 pF, V _I = 1 MHz, –1-dB FS		1.5	2.6	mA	
		DRV _{DD}			4	6	
D _	Dower dissipation		PWDN_REF = L		106	139	
P _D Power dissipation			PWDN_REF = H		90	113	mW
PD(STBY)	Standby power		STBY = H, CLK held high or low		11	15	

digital logic inputs

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
IIH	High-level input current on CLK [†]	$AV_{DD} = DV_{DD} = DRV_{DD} = CLK = 3.6$ V			10	μΑ
١ _١ ٢	Low-level input current on digital inputs (OE, STDBY, PWDN_REF, CLK)	$AV_{DD} = DV_{DD} = DRV_{DD} = 3.6 V,$ Digital inputs at 0 V			10	μA
CI	Input capacitance			5		pF

[†] I_{IH} leakage current on other digital inputs (OE, STDBY, PWDN_REF) is not measured since these inputs have an internal pull-down resistor of 4 KΩ to DGND.



SGLS29/11-17-NU/BS2094-PPEV4507778 E 2008

electrical characteristics over recommended operating conditions, f_{CLK} = 35 MSPS, external voltage references (unless otherwise noted) (continued)

logic outputs

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VOH	High-level output voltage	$AV_{DD} = DV_{DD} = DRV_{DD} = 3$ V at $I_{OH} = 50 \mu A$, Digital output forced high	2.8			V
VOL	Low-level output voltage	$AV_{DD} = DV_{DD} = DRV_{DD} = 3.6 \text{ V} \text{ at } I_{OL} = 50 \mu\text{A},$ Digital output forced low			0.1	V
CO	Output capacitance			5		pF
IOZH	High-impedance state output current to high level				10	μΑ
I _{OZL}	High-impedance state output current to low level	$AV_{DD} = DV_{DD} = DRV_{DD} = 3.6 V$			10	μΑ

dc accuracy

PARAMETER	TEST CONDITIONS			TYP	MAX	UNIT
	Internal references (see Note 1)	$T_A = 25^{\circ}C$	-1.5	±0.7	1.5	LSB
Integral nonlinearity (INL), best-fit		$T_A = -40^{\circ}C$ to $85^{\circ}C$	-2.4	±0.7	2.4	LSB
Differential nonlinearity (DNL)	Internal references (see Note 2),	$T_A = -40^{\circ}C$ to $85^{\circ}C$	-1	±0.6	1.3	LSB
Zero error	$AV_{DD} = DV_{DD} = 3.3 \text{ V}, DRV_{DD} = 3 \text{ V},$				5	%FS
Full-scale error	Internal references (see Note 3)				5	%FS

NOTES: 1. Integral nonlinearity refers to the deviation of each individual code from a line drawn from zero to full scale. The point used as zero occurs 1/2 LSB before the first code transition. The full-scale point is defined as a level 1/2 LSB beyond the last code transition. The deviation is measured from the center of each particular code to the true straight line between these two endpoints.

2. An ideal ADC exhibits code transitions that are exactly 1 LSB apart. DNL is the deviation from this ideal value. Therefore this measure indicates how uniform the transfer function step sizes are. The ideal step size is defined here as the step size for the device under test [i.e., (last transition level – first transition level) ÷ (2ⁿ – 2)]. Using this definition for DNL separates the effects of gain and offset error. A minimum DNL better than –1 LSB ensures no missing codes.

3. Zero error is defined as the difference in analog input voltage – between the ideal voltage and the actual voltage – that switches the ADC output from code 0 to code 1. The ideal voltage level is determined by adding the voltage corresponding to 1/2 LSB to the bottom reference level. The voltage corresponding to 1 LSB is found from the difference of top and bottom references divided by the number of ADC output levels (256).

Full-scale error is defined as the difference in analog input voltage – between the ideal voltage and the actual voltage – that switches the ADC output from code 254 to code 255. The ideal voltage level is determined by subtracting the voltage corresponding to 1.5 LSB from the top reference level. The voltage corresponding to 1 LSB is found from the difference of top and bottom references divided by the number of ADC output levels (256).

analog input

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
CI	Input capacitance			4		pF



查询"TI V5535-Q1"供应商

SGLS230A - JANUARY 2004 - REVISED JUNE 2008

electrical characteristics over recommended operating conditions, f_{CLK} = 35 MSPS, external voltage references (unless otherwise noted) (continued)

reference input (AV_{DD} = DV_{DD} = DRV_{DD} = 3.6 V)

PARAMETER		PARAMETER TEST CONDITIONS		TYP	MAX	UNIT
R _{ref}	Reference input resistance			400		Ω
Iref	Reference input current			2.5		mA

reference outputs

	PARAMETER	TEST CONDITIONS	MIN	ТҮР	MAX	UNIT
V(REFTO)	Reference top offset voltage	Absolute min/max values valid	2.07	$2 + [(AV_{DD} - 3) \div 2]$	2.21	V
V _(REFBO)	Reference bottom offset voltage	and tested for AV _{DD} = 3.3 V	1.09	$1 + [(AV_{DD} - 3) \div 2]$	1.21	V

dynamic performance[†]

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	f _{in} = 1 MHz	6.6	7.4		
Effective number of bits (ENOB)	f _{in} = 4.2 MHz	6.6	7.4		Bits
	f _{in} = 15 MHz		7		
	f _{in} = 1 MHz	41.5	46		
Signal-to-noise ratio + distortion (SNRD)	f _{in} = 4.2 MHz	41.5	46		dB
	f _{in} = 15 MHz		43		
	f _{in} = 1 MHz	-46	-55		
Total harmonic distortion (THD)	f _{in} = 4.2 MHz	-45.5	-54		dB
	f _{in} = 15 MHz		-50		
	f _{in} = 1 MHz	48	58		
Spurious free dynamic range (SFDR)	$f_{in} = 4.2 \text{ MHz}$	48	58		dB
	f _{in} = 15 MHz		52		
Analog input full-power bandwidth, BW	See Note 4		600		MHz
Differential phase, DP	f _{CLK} = 35 MHz, f _{in} = 4.2 MHz,		0.6 [°]		
Differential gain, DG	20 IRE amplitude vs full-scale of 140 IRE		0.2%		

[†]Based on analog input voltage of -1-dB FS referenced to a 1.3 V_{pp} full-scale input range and using the external voltage references at $f_{CLK} = 35 \text{ MSPS}$ with $AV_{DD} = DV_{DD} = 3.3 \text{ V}$ and $DRV_{DD} = 3 \text{ V}$ at $25^{\circ}C$. NOTE 4: The analog input bandwidth is defined as the maximum frequency of a -1-dB FS input sine that can be applied to the device for which

an extra 3-dB attenuation is observed in the reconstructed output signal.



SGLS250/17-17-NU/ABS2004-PPEV/#FD77788E 2008

electrical characteristics over recommended operating conditions, f_{CLK} = 35 MSPS, external voltage references (unless otherwise noted) (continued)

timing requirements

	PARAMETER	TEST	TEST CONDITIONS		TYP	MAX	UNIT
	Maximum conversion rate			35			MHz
^f CLK	Minimum conversion rate					10	kHz
^t d(o)	Output delay time (see Figure 1)	C _L = 10 pF,	See Notes 5 and 6			9	ns
^t h(o)	Output hold time	C _L = 2 pF,	See Note 5	2			ns
^t d(pipe)	Pipeline delay time (latency)	See Note 6		4.5	4.5	4.5	CLK cycles
^t d(a)	Aperture delay time				3		ns
^t j(a)	Aperture jitter	See Note 5			1.5		ps, rms
^t dis	Disable time, OE rising to Hi-Z	See Note 5			5	8	ns
t _{en}	Enable time, OE falling to valid data				5	8	ns

NOTES: 5. Output timing t_{d(0)} is measured from the 1.5 V level of the CLK input falling edge to the 10%/90% level of the digital output. The digital output load is not higher than 10 pF.

Output hold time $t_{h(0)}$ is measured from the 1.5 V level of the CLK input falling edge to the 10%/90% level of the digital output. The digital output is load is not less than 2 pF.

Aperture delay t_{d(A)} is measured from the 1.5 V level of the CLK input to the actual sampling instant.

The OE signal is asynchronous.

OE timing t_{dis} is measured from the V_{IH(MIN)} level of OE to the high-impedance state of the output data. The digital output load is not higher than 10 pF.

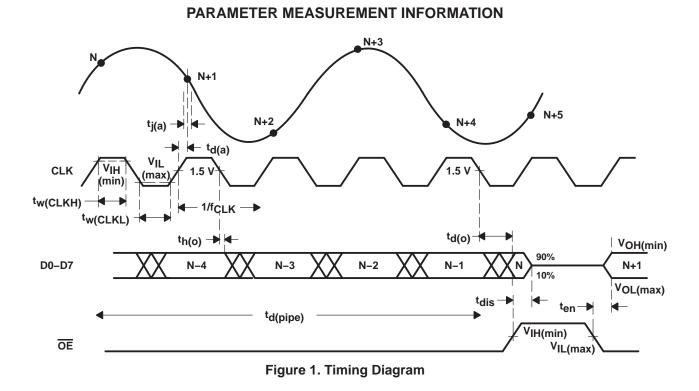
OE timing t_{en} is measured from the V_{IL(MAX)} level of OE to the instant when the output data reaches V_{OH(min)} or V_{OL(max)} output levels. The digital output load is not higher than 10 pF.

6. The number of clock cycles between conversion initiation on an input sample and the corresponding output data being made available from the ADC pipeline. Once the data pipeline is full, new valid output data is provided on every clock cycle. In order to know when data is stable on the output pins, the output delay time t_{d(0)} (i.e., the delay time through the digital output buffers) needs to be added to the pipeline latency. Note that since the max t_{d(0)} is more than 1/2 clock period at 35 MHz, data cannot be reliably clocked in on a rising edge of CLK at this speed. The falling edge should be used.



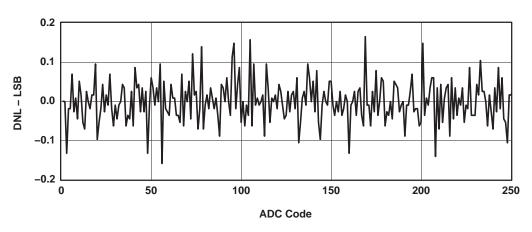
SGLS230A - JANUARY 2004 - REVISED JUNE 2008

查询"TI V5535-Q1"供应商



TYPICAL CHARACTERISTICS

performance plots at 25°C







SGLS2967HUMB52004 OPEVERTIME 2008



performance plots at 25°C (continued)

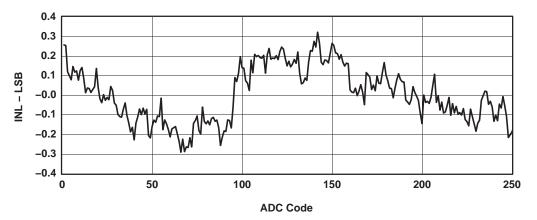


Figure 3. INL vs Input Code at 35 MSPS (with external reference, PW package)

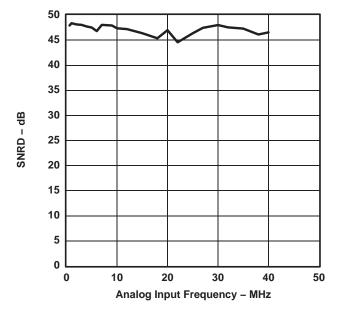


Figure 4. SNRD vs f_{in} at 35 MSPS (external reference)



<u> 查询"TLV5535-Q1"供应商</u>

SGLS230A - JANUARY 2004 - REVISED JUNE 2008

TYPICAL CHARACTERISTICS

performance plots at 25°C (continued)

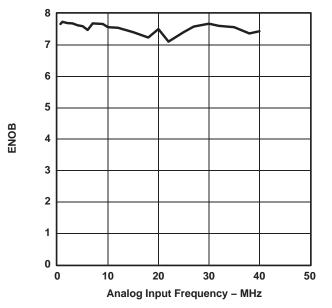


Figure 5. ENOB vs FIN, 35 MSPS (external reference)

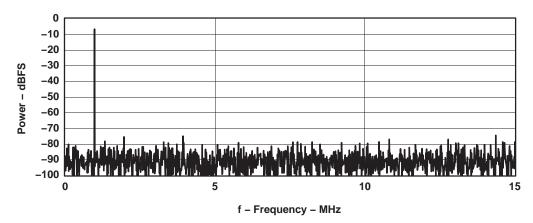


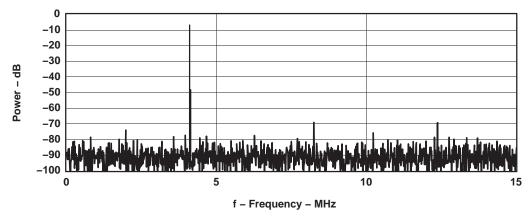
Figure 6. Spectral Plot f_{in} = 1.0 MHz at 35 MSPS



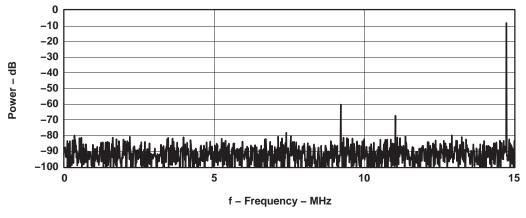
SGLS2901117NUAB52094092149071777E 2008

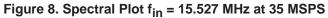
TYPICAL CHARACTERISTICS

performance plots at 25°C (continued)











<u> 查询"TLV5535-Q1"供应商</u>

SGLS230A - JANUARY 2004 - REVISED JUNE 2008

TYPICAL CHARACTERISTICS

performance plots at 25°C (continued)

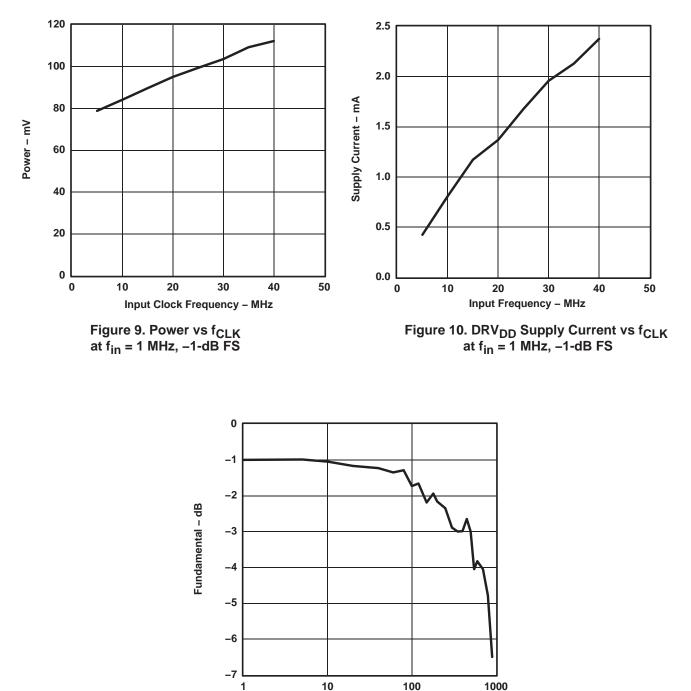


Figure 11. ADC Output Power With Respect to –1-dB FS V_{IN} (internal reference, PW package)

Input Frequency – MHz



SGLS AT JANUARS 2004 OF EVERT E 2008

PRINCIPLES OF OPERATION

The TLV5535 implements a high-speed 35 MSPS converter in a cost-effective CMOS process. Powered from 3.3 V, the single-pipeline design architecture ensures low-power operation and 8-bit accuracy. Signal input and clock signals are all single-ended. The digital inputs are 3.3-V TTL/CMOS compatible. Internal voltage references are included for both bottom and top voltages. Therefore the converter forms a self-contained solution. Alternatively, the user may apply externally generated reference voltages. In doing so, both input offset and input range can be modified to suit the application.

A high-speed sampling-and-hold captures the analog input signal. Multiple stages generate the output code with a pipeline delay of 4.5 CLK cycles. Correction logic combines the multistage data and aligns the 8-bit output word. All digital logic operates at the rising edge of CLK.

analog input

A first-order approximation for the equivalent analog input circuit of the TLV5535 is shown in Figure 12. The equivalent input capacitance C_I is 4 pF typical. The input must charge/discharge this capacitance within the sample period of one half clock cycle. When a full-scale voltage step is applied, the input source provides the charging current through the switch resistance R_{SW} (200 Ω) of S1 and quickly settles. In this case, the input impedance is low. Alternatively, when the source voltage equals the value previously stored on C_I , the hold capacitor requires no input current and the equivalent input impedance is very high.

To maintain the frequency performance outlined in the specifications, the total source impedance should be limited to about 80 Ω , as follows from the equation with f_{CLK} = 35 MHz, C_I = 4 pF, R_{SW} = 200 Ω :

 $R_{S} < \left[1 \div \left(2f_{CLK} \times C_{I} \times In(256)\right) - R_{SW}\right]$ The source impedance is approximatly 450 Ω.



<u> 查询"TLV5535-Q1"供应商</u>

SGLS230A - JANUARY 2004 - REVISED JUNE 2008

PRINCIPLE OF OPERATION

analog input (continued)

So, for applications running at a lower f_{CLK}, the total source resistance will increase proportionally.

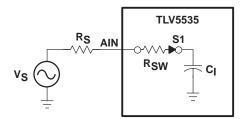


Figure 12. Simplified Equivalent Input Circuit

dc coupled input

For dc-coupled systems an op amp can level-shift a ground-referenced input signal. A circuit as shown in Figure 13(a) is acceptable. Alternatively, the user might want a bipolar shift together with the bottom reference voltage as seen in Figure 13(b). In this case the AIN voltage is given by:

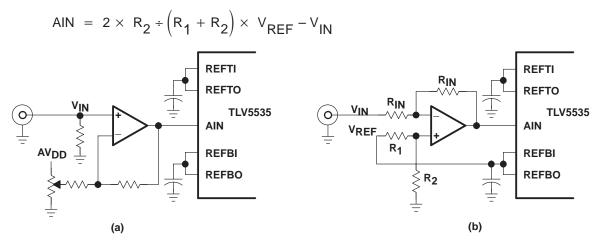


Figure 13. DC-Coupled Input Circuit

ac coupled input

For many applications, especially in single supply operation, ac coupling offers a convenient way for biasing the analog input signal at the proper signal range. Figure 14 shows a typical configuration. To maintain the outlined specifications, the component values need to be carefully selected. The most important issue is the positioning of the 3-dB high-pass corner point $f_{-3 dB}$, which is a function of R_2 and the parallel combination of C_1 and C_2 , called C_{eq} . This is given by the following equation:

$$f_{-3 \text{ dB}} = 1 \div (2\pi \times R_2 \times C_{eq})$$

where C_{eq} is the parallel combination of C_1 and C_2 .



SGLS2301117NUAB52094 OPE HEITURE 2008

Since C1 is typically a large electrolytic or tantalum capacitor, the impedance becomes inductive at higher frequencies. Adding a small ceramic or polystyrene capacitor, C2 of approximately 0.01 μ F, which is not inductive within the frequency range of interest, maintains low impedance. If the minimum expected input signal frequency is 20 kHz, and R2 equals 1 k Ω and R1 equals 50 Ω , the parallel capacitance of C1 and C2 must be a minimum of 8 nF to avoid attenuating signals close to 20 kHz.



<u> 查询"TLV5535-Q1"供应商</u>

SGLS230A - JANUARY 2004 - REVISED JUNE 2008

PRINCIPLE OF OPERATION

ac coupled input (continued)

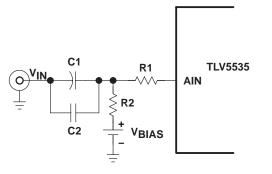


Figure 14. AC-Coupled Input Circuit

reference terminals

The voltages on terminals REFBI and REFTI determine the TLV5535 input range. Since the device has an internal voltage reference generator with outputs available on REFBO and REFTO respectively, corresponding terminals can be directly connected externally to provide a contained ADC solution. Especially at higher sampling rates, it is advantageous to have a wider analog input range. The wider analog input range is achievable by using external voltage references (e.g., at AV_{DD} = 3.3 V, the full-scale range can be extended from 1 V_{pp} (internal reference) to 1.3 V_{pp} (external reference) as shown in Table 1). These voltages should not be derived via a voltage divider from a power supply source. Instead, a bandgap-derived voltage reference should be used to derive both references via an op amp circuit. Refer to the schematic of the TLV5535 evaluation module for an example circuit.

When using external references, the full-scale ADC input range and its dc position can be adjusted. The full-scale ADC range is always equal to $V_{REFT} - V_{REFB}$. The maximum full-scale range is dependent on AV_{DD} as shown in the specification section. In addition to the limitation on their difference, V_{REFT} and V_{REFB} each also have limits on their useful range. These limits are also dependent on AV_{DD} .

Table 1 summarizes these limits for 3 cases.

AVDD	V _{REFB} (min)	V _{REFB(max)}	V _{REFT(min)}	V _{REFT(max)}	(V _{REFT} -V _{REFB}) _{max}
3 V	0.8 V	1.2 V	1.8 V	2.2 V	1 V
3.3 V	0.8 V	1.2 V	2.1 V	2.5 V	1.3 V
3.6 V	0.8 V	1.2 V	2.4 V	2.8 V	1.6 V

Table 1. Recommended Operating Modes

digital inputs

The digital inputs are CLK, STDBY, PWDN_REF, and \overline{OE} . All of these signals, except CLK, have an internal pulldown resistor to connect to digital ground. This provides a default active operation mode using internal references when left unconnected.



SGLS 201 TANUARS 2004 OF EVEL DIT TO BE 2008

PRINCIPLE OF OPERATION

digital inputs (continued)

The CLK signal at high frequencies should be considered as an analog input. Overshoot/undershoot should be minimized by proper termination of the signal close to the TLV5535. An important cause of performance degradation for a high-speed ADC is clock jitter. Clock jitter causes uncertainty in the sampling instant of the ADC, in addition to the inherent uncertainty on the sampling instant caused by the part itself, as specified by its aperture jitter. There is a theoretical relationship between the frequency (f) and resolution (2^N) of a signal that needs to be sampled and the maximum amount of aperture error dt_{max} that is tolerable. The following formula shows the relation:

$$dt_{max} = 1 \div \left[\pi f 2^{(N+1)}\right]$$

As an example, for an 8-bit converter with a 15-MHz input, the jitter needs to be kept < 41 pF in order not to have changes in the LSB of the ADC output due to the total aperture error.

digital outputs

The output of the TLV5535 is standard binary code. Capacitive loading on the output should be kept as low as possible (a maximum loading of 10 pF is recommended) to provide the best performance. Higher output loading causes higher dynamic output currents and can increase noise coupling into the analog front end of the device. To drive higher loads, the use of an output buffer is recommended.

When clocking output data from the TLV5535, it is important to observe its timing relation to CLK. The pipeline ADC delay is 4.5 clock cycles to which the maximum output propagation delay is added. See Note 6 in the specification section for more details.

layout, decoupling and grounding rules

It is necessary for any PCB using the TLV5535 to have proper grounding and layout to achieve the stated performance. Separate analog and digital ground planes that are spliced underneath the device are advisable. The TLV5535 has digital and analog terminals on opposite sides of the package to make proper grounding easier. Since there is no internal connection between the analog and digital grounds, they have to be joined on the PCB. Joining the digital and analog grounds at a point in close proximity to the TLV5535 is advised.

As for power supplies, separate analog and digital supply terminals are provided on the device (AV_{DD}/DV_{DD}) . The supply to the digital output drivers is kept separate also (DRV_{DD}) . Lowering the voltage on this supply from the nominal 3.3 V to 3 V improves performance because of the lower switching noise caused by the output buffers.

Due to the high sampling rate and switched-capacitor architecture, the TLV5535 generates transients on the supply and reference lines. Proper decoupling of these lines is essential. Decoupling as shown in the schematic of the TLV5535 EVM is recommended.



TLV5535 EVALUATION MODULE

TLV5535 evaluation module

TI provides an evaluation module (EVM) for TLV5535. The EVM also includes a 10b 80 MSPS DAC so that the user can convert the digitized signal back to the analog domain for functional testing. Performance measurements can be done by capturing the ADC's output data.

The EVM provides the following additional features:

- Provision of footprint for the connection of an onboard crystal oscillator, instead of using an external clock input.
- Use of TLV5535 internal or external voltage references. In the case of external references, an onboard circuit is used that derives adjustable bottom and top reference voltages from a bandgap reference. Two potentiometers allow for the independent adjustments of both references. The full scale ADC range can be adjusted to the input signal amplitude.
- All digital output, control signal I/O (output enable, standby, reference powerdown) and clock I/O are provided on a single connector. The EVM can thus be part of a larger (DSP) system for prototyping.
- Onboard prototyping area with analog and digital supply and ground connections.

Figure 15 shows the EVM schematic.

The EVM is factory shipped for use in the following configuration:

- Use of external (onboard) voltage references
- External clock input

analog input

A signal in the range between $V_{(REFBI)}$ and $V_{(REFTI)}$ should be applied to avoid overflow/underflow on connector J10. This signal is onboard terminated with 50 Ω . There is no onboard biasing of the signal. When using external (onboard) references, these levels can be adjusted with R7 ($V_{(REFTI)}$) and R6 ($V_{(REFBI)}$). Adjusting R7 causes both references to shift. R6 only impacts the bottom reference. The range of these signals for which the device is specified depends on AV_{DD} and is shown in the *Recommended Operating Conditions*.

Internally generated reference levels are also dependent on AV_{DD} as shown in the electrical characteristics section.

clock input

A clock signal should be applied with amplitudes ranging from 0 to AV_{DD} with a frequency equal to the desired sampling frequency on connector J9. This signal is onboard terminated with 50 Ω . Both ADC and DAC run off the same clock signal. Alternatively the clock can be applied from terminal 1 on connector J11. A third option is using a crystal oscillator. The EVM board provides the footprint for a crystal oscillator that can be populated by the end-user, depending on the desired frequency. The footprint is compatible with the Epson EG-8002DC series of programmable high-frequency crystal oscillators. Refer to the TLV5535 EVM Settings for selecting between the different clock modes.



SGLS201 TANUARS 2004 OPEVILED TO BE 2008

TLV5535 EVALUATION MODULE

power supplies

The board provides seven power supply connectors (see Table 2). For optimum performance, analog and digital supplies should be kept separate. Using separate supplies for the digital logic portion of TLV5535 (DV_{DD}) and its output drivers (DRV_{DD}) benefits dynamic performance, especially when DRV_{DD} is put at the minimum required voltage (3 V), while DV_{DD} might be higher (up to 3.6 V). This lowers the switching noise on the die caused by the output drivers.

SIGNAL NAME	CONNECTOR	BOARD LABEL	DESCRIPTION
DRV3	J1	3DRV	3.3 V digital supply for TLV5535 (digital output drivers)
DV3	J2	3VD	3.3 V digital supply for TLV5535 (digital logic) and peripherals
DV5	J3	5VD	5 V digital supply for D/A converter and peripherals
AV3	J4	3VA	3.3 V analog supply for TLV5535
AV5	J5	5VA	5 V analog supply for onboard reference circuit and D/A converter. Can be left unconnected if internal references are used and no D/A conversion is required.
AV+12	J6	12VA	12 V analog supply for onboard reference circuit. Can be left unconnected if internal references are used.
AV-12	J7	-12VA	-12 V analog supply for onboard reference circuit. Can be left unconnected if internal references are used.

Table 2. Power Supplies

voltage references

SW1 and SW2 switch between internal and external top and bottom references respectively. The external references are onboard generated from a stable bandgap-derived 3.3 V signal (using TI's TPS7133 and quad-opamp TLE2144). They can be adjusted via potentiometers R6 ($V_{(REFBI)}$) and R7 ($V_{(REFTI)}$). It is advised to power down the internal voltage references by asserting PWN_REF when onboard references are used.

The references are measured at test points TP3 ($V_{(REFB)}$) and TP4 ($V_{(REFT)}$).

DAC output

The onboard DAC is a 10-bit 80 MSPS converter. It is connected back-to-back to the TLV5535. While the user could use its analog output for measurements, the DAC output is directly connected to connector J8 and does not pass through an analog reconstruction filter. So mirror spectra from aliased signal components feed through into the analog output.

For this reason and to separate ADC and DAC contributions, performance measurements should be made by capturing the ADC output data available on connector J11 and not by evaluating the DAC output.



SGLS230A - JANUARY 2004 - REVISED JUNE 2008

TLV5535 EVALUATION MODULE

TLV5535 EVM settings

clock input settings

REFERENCE DESIGNATOR	FUNCTION
W1	Clock selection switch 1–2 J11: clock from pin1 on J11 connector 2–3 J9: clock from J9 SMA connector
W2	Clock source switch XTL: clock from onboard crystal oscillator CLK: clock from pin 1 on J11 connector (if W1/1–2) or J9 SMA connector (if W1/2–3) NOTE: If set to XTL and a XTL oscillator is populated, no clock signal should be applied to J9 or J11, depending on the W1 setting.
W3	Clock output switch 1–2 Rising: clock output on J11 connector is the same phase as the clock to the digital output buffer. Data changes on rising CLK edge. 2–3 Falling: clock output on J11 connector is the opposite phase as the digital output buffer. Data changes on falling CLK edge.

reference settings

REFERENCE DESIGNATOR	FUNCTION
SW1	REFT external/internal switch ■ REFT internal: REFT from TLV5535 internal reference □ REFT external: REFT from onboard voltage reference circuit
SW2	REFB external/internal switch ■ REFB internal: REFB from TLV5535 internal reference □ REFB external: REFB from onboard voltage reference circuit

control settings

REFERENCE DESIGNATOR	FUNCTION
W4	 TLV5535 and digital output buffer output enable control (1) ■ 5535-574 OE-connected: Connects OEs of TLV5535 and digital output buffer (574 buffer). Use this when no board-external OE is used. In addition, close W5 to have both OEs permanently enabled.
	5535-574 OE-disconnected: Disconnects OEs of TLV5535 and digital output buffer (574 buffer). The OE for the output buffer needs to be pulled low from pin 5 on J11 connector to enable. The OE for TLV5535 is independently controlled from pin 7 on J11 connector (W5 open) or is permanently enabled if W5 is closed.
W5	TLV5535 and digital output buffer output enable control (2) ■ 5535 OE to GND: Connects OEs of TLV5535 to GND. Additionally connects OE of 74ALS574 to GND if W4 is 5535-574 OE-connected.
	□ 5535 OE external: Enables control of OE of TLV5535 via pin 7 on J11 connector. When taken high (internal pulldown) the output can be disabled.
W6	TLV5535 STDBY control ■ Stdby: STDBY is active (high).
	□ Active: STDBY is low, via internal pulldown. STDBY can be taken high from pin 9 on J11 connector to enable standby mode.



SGLS23017-JANUARS2004 OREVERTUBE 2008

TLV5535 EVALUATION MODULE

control settings (continued)

REFERENCE DESIGNATOR	FUNCTION
W7	TLV5535 PWDN REF control ■ Pwdn_ref: PWDN_REF is active (high).
	□ Active: PWDN_REF is low, via internal pulldown. PWDN_REF can be taken high from pin 10 on J11 connector to enable pwdn_ref mode.
W8	DAC enable ■ Active: D/A on
	Standby: D/A off



SGLS230A - JANUARY 2004 - REVISED JUNE 2008

查询"TI V5535-Q1"供应商

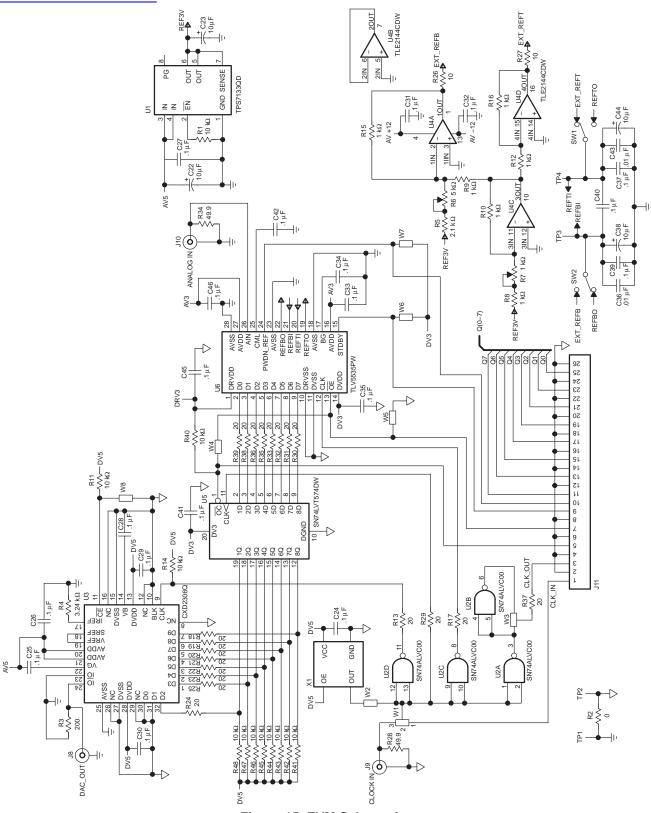
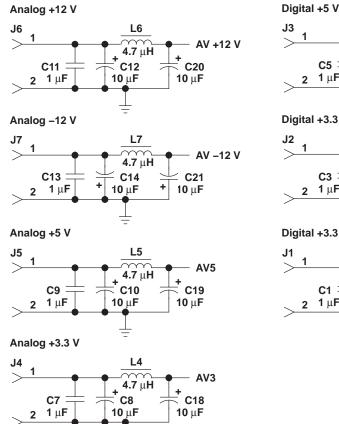


Figure 15. EVM Schematic

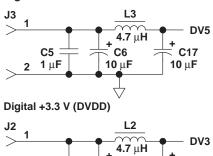


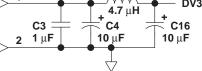
SGLS 26 (1) TANU / F 5 2 () 4 () 4 () 1 ()



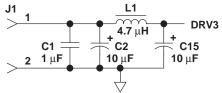
Ŧ

TLV5535 EVALUATION MODULE





Digital +3.3 V (DRVDD)

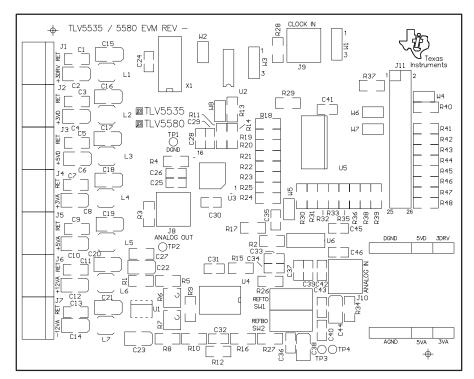






SGLS230A - JANUARY 2004 - REVISED JUNE 2008

<u> 查询"TLV5535-Q1"供应商</u>

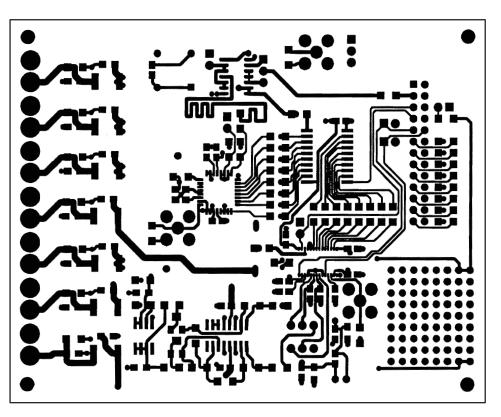


TLV5535 EVALUATION MODULE

Figure 16. EVM Board Layout, Top Overlay



SGLS23017-JANUARS 2004 OREVERTURE 2008



TLV5535 EVALUATION MODULE

Figure 17. EVM Board Layout, Top Layer



റ

000000000

000

0(

00

SGLS230A - JANUARY 2004 - REVISED JUNE 2008

查询"TI V5535-Q1"供应商

0

•

0

0

000

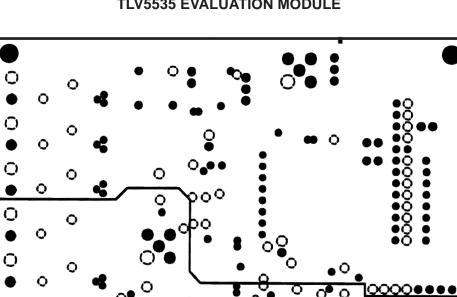
О

0

0

0

0



TLV5535 EVALUATION MODULE

Figure 18. EVM Board Layout, Internal Plane 1

 \cap

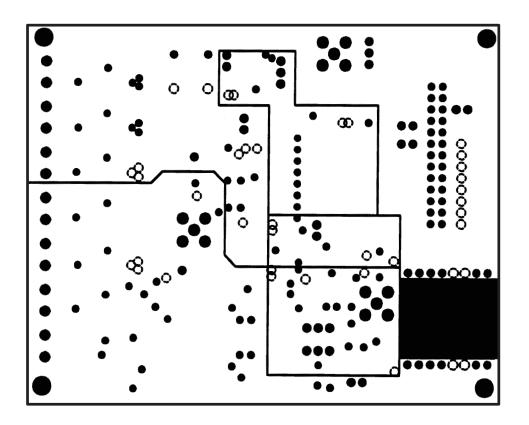
O)

00

00



SGLS23017-JANUARS2004 OREVERTUBE 2008



TLV5535 EVALUATION MODULE

Figure 19. EVM Board Layout, Internal Plane 2



SGLS230A - JANUARY 2004 - REVISED JUNE 2008

<u> 查询"TLV5535-Q1"供应商</u>

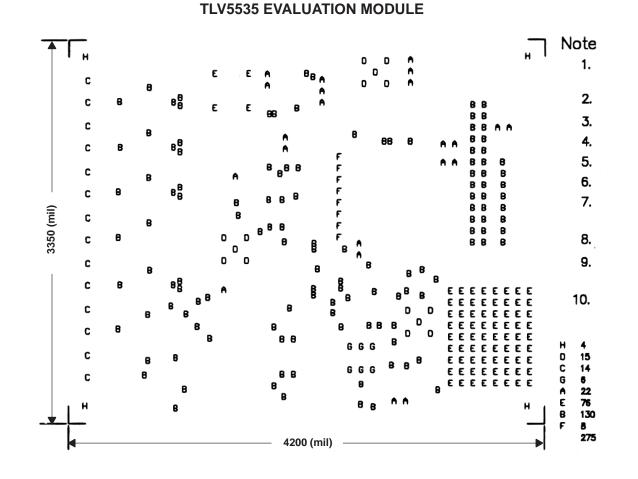


Figure 20. EVM Board Layout, Drill Drawing for Through Hole



SGLS23017-JANUARS2004 OREVERTUBE 2008



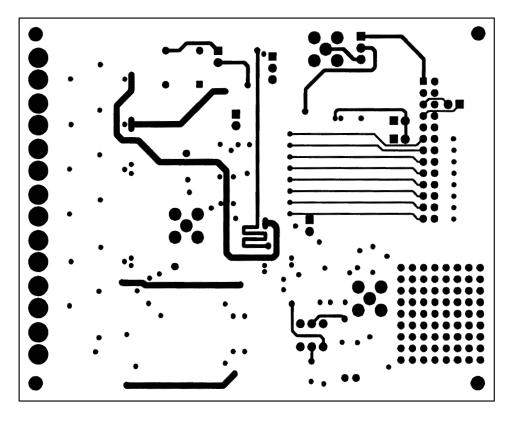


Figure 21. EVM Board Layout, Bottom Layer



<u> 查询"TLV5535-Q1"供应商</u>

SGLS230A - JANUARY 2004 - REVISED JUNE 2008

TLV5535 EVALUATION MODULE

Table 3. TLV5535EVM Bill of Material

QTY.	REFERENCE DESIGNATOR	VALUE	SIZE	DESCRIPTION	MANUFACTURER/ PART NUMBER [†]
7	C1, C11, C13, C3, C5, C7, C9	1 μF	1206	ceramic multilayer capacitor	Any
18	C10, C12, C14, C15, C16, C17, C18, C19, C2, C20, C21, C22, C23, C4, C6, C8, C38, C44	10 μF	3216	16 V, 10 μF , tantalum capacitor	Any
2	C36, C43	0.01 μF	805	Ceramic multilayer	Any
19	C24, C25, C26, C27, C28, C29, C30, C31, C32, C33, C34, C35, C37, C39, C40, C41, C42, C45, C46	0.1 μF	805	Ceramic multilayer capacitor	Any
7	J1, J2, J3, J4, J5, J6, J7	Screw Con		2 terminal screw connector	Lumberg KRMZ2
3	J10, J8, J9	SMA		PCM mount, SMA Jack	Johnson Components 142-0701-206
1	J11	IDC26		$13'' \times 2.025''$ square pin header	Samtec TSW-113-07-L-D
7	L1, L2, L3, L4, L5, L6, L7	4.7 μΗ		4.7 μH DO1608C-472-Coil Craft	Coil Craft DO1608-472
1	R2	0	1206	Chip resistor	Any
2	R26, R27	10	1206	Chip resistor	Any
12	R1, R11, R14, R40, R41, R42, R43, R44, R45, R46, R47, R48	10 K	1206	Chip resistor	Any
6	R10, R12, R15, R16, R8, R9	1 K	1206	Chip resistor	Any
1	R5	2.1 K	1206	Chip resistor	Any
20	R13, R17, R18, R19, R20, R21, R22, R23, R24, R25, R29, R30, R31, R32, R33, R35, R36, R37, R38, R39	20	1206	Chip resistor	Any
1	R3	200	1206	Chip resistor	Any
1	R4	3.24 K	1206	Chip resistor	Any
2	R28, R34	49.9	1206	Chip resistor	Any
1	R6	5 K		4 mm SM pot-top adjust	Bourns 3214W-5K
1	R7	1 K		4 mm SM pot-top adjust	Bourns 3214W-1K
2	SW1, SW2	SPDT		C&K tiny series-slide switch	C&K TS01CLE
4	TP1, TP2, TP3, TP4	TP		Test point, single 0.025" pin	Samtec TSW-101-07-L-S or equivalent
1	U3	CXD2306Q			Sony CXD2306Q
1	U2	SN74ALVC00D	14-SOIC (D)	Quad 2-input positive NAND	Texas Instruments SN74ALVC00D
1	U5	SN74LVT574DW	20-SOP (DW)		Texas Instruments SN74LVT574DW

[†] Manufacturer and part number data for reference only. Equivalent parts might be substituted on the EVM.



SGLS23017-JANUARS2004 OREVERTUBE 2008

TLV5535 EVALUATION MODULE

QTY.	REFERENCE DESIGNATOR	VALUE	SIZE	DESCRIPTION	MANUFACTURER/ PART NUMBER [†]
1	U4	TLE2144CDW	16-SOP(D)	Quad op amp	Texas Instruments TLE2144CDW/ TLE2144IDW
1	U6	TLV5535PW	28-TSSOP (PW)		Texas Instruments TLV5535PW
1	U1	TPS7133	8-SOP(D)	Low-dropout voltage regulator	Texas Instruments TPS7133QD
6	W2, W4, W5, W6, W7, W8	SPST		2 position jumper, 0.1" spacing	Samtec TSW-102-07-L-S or equivalent
2	W1, W3	DPFT		3 position jumper, 0.1" spacing	Samtec TSW-103-07-L-S or equivalent
1	X1	NA		Crystal oscillator	Epson SG-8002DC series

Table 3. TLV5535EVM Bill of Material (Continued)

[†] Manufacturer and part number data for reference only. Equivalent parts might be substituted on the EVM.



PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
TLV5535IPWRG4Q1	ACTIVE	TSSOP	PW	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5535IPWRQ1	ACTIVE	TSSOP	PW	28	2000	TBD	CU NIPDAU	Level-1-220C-UNLIM

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details. TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

Important Information and Disclaimer:The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF TLV5535-Q1 :

Catalog: TLV5535

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product

MECHANICAL DATA

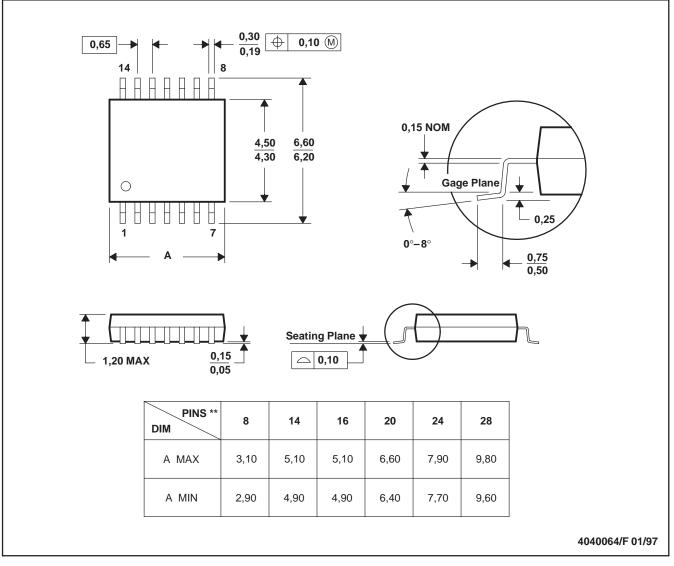
<u> 查询"TLV5535-Q1"供应商</u>

MTSS001C - JANUARY 1995 - REVISED FEBRUARY 1999

PLASTIC SMALL-OUTLINE PACKAGE

PW (R-PDSO-G**)

14 PINS SHOWN



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.
- D. Falls within JEDEC MO-153



查询"TLV5535-Q1"供应商

IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

TI products are not authorized for use in safety-critical applications (such as life support) where a failure of the TI product would reasonably be expected to cause severe personal injury or death, unless officers of the parties have executed an agreement specifically governing such use. Buyers represent that they have all necessary expertise in the safety and regulatory ramifications of their applications, and acknowledge and agree that they are solely responsible for all legal, regulatory and safety-related requirements concerning their products and any use of TI products in such safety-critical applications, notwithstanding any applications-related information or support that may be provided by TI. Further, Buyers must fully indemnify TI and its representatives against any damages arising out of the use of TI products in such safety-critical applications.

TI products are neither designed nor intended for use in military/aerospace applications or environments unless the TI products are specifically designated by TI as military-grade or "enhanced plastic." Only products designated by TI as military-grade meet military specifications. Buyers acknowledge and agree that any such use of TI products which TI has not designated as military-grade is solely at the Buyer's risk, and that they are solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI products are neither designed nor intended for use in automotive applications or environments unless the specific TI products are designated by TI as compliant with ISO/TS 16949 requirements. Buyers acknowledge and agree that, if they use any non-designated products in automotive applications, TI will not be responsible for any failure to meet such requirements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

Products		Applications	
Amplifiers	amplifier.ti.com	Audio	www.ti.com/audio
Data Converters	dataconverter.ti.com	Automotive	www.ti.com/automotive
DSP	dsp.ti.com	Broadband	www.ti.com/broadband
Clocks and Timers	www.ti.com/clocks	Digital Control	www.ti.com/digitalcontrol
Interface	interface.ti.com	Medical	www.ti.com/medical
Logic	logic.ti.com	Military	www.ti.com/military
Power Mgmt	power.ti.com	Optical Networking	www.ti.com/opticalnetwork
Microcontrollers	microcontroller.ti.com	Security	www.ti.com/security
RFID	www.ti-rfid.com	Telephony	www.ti.com/telephony
RF/IF and ZigBee® Solutions	www.ti.com/lprf	Video & Imaging	www.ti.com/video
		Wireless	www.ti.com/wireless

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2008, Texas Instruments Incorporated